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# AS7C34098A-8TIN 256K X 16 BIT HIGH SPEED CMOS SRAM

## **REVISION HISTORY**

Revision	<u>Description</u>	Issue Date
Rev. 1.0	Initial Issue	Jul.12.2012
Rev. 1.1	"CE# $\geq$ V <sub>CC</sub> - 0.2V" revised as "CE# $\leq$ 0.2V" for <b>TEST CONDITION</b>	Jul.19.2012
	of Average Operating Power supply Current	
	lcc1 on page3	
Rev. 1.2	Revised $V_{IH(max)}/V_{IL(min)}$ in	May.7.2013
	DC ELECTRICAL CHARACTERISTICS	
	Added in t <sub>BA</sub> /t <sub>BHZ*</sub> /t <sub>BLZ*</sub>	
	in AC ELECTRICAL CHARACTERISTICS	
	Added WRITE CYCLE 3 in TIMING WAVEFORMS	
Rev. 1.3	1. Revise " <b>TEST CONDITION</b> " for V <sub>OH</sub> , V <sub>OL</sub> on page 5	Jun.04.2013
	I <sub>OH</sub> = -8mA revised as -4mA	
	I <sub>OL</sub> =4mA revised as 8mA	
	2. Revise V <sub>IH(max)</sub> & V <sub>IL(min)</sub> note on page 5	
	$V_{IH(max)} = V_{CC} + 2.0V$ for pulse width less than 6ns.	
	$V_{IL(min)} = V_{SS} - 2.0V$ for pulse width less than 6ns.	
Rev. 1.4	Revised the address pin sequence of TSOP-II pin configuration on	Sep.23.2013
	page 3 in order to be compatible with industry convention. (No	
	function specifications and applications have been changed and all	
	the characteristics are kept all the same as Rev 1.3 )	
	Added t <sub>BW</sub> in <b>AC ELECTRICAL CHARACTERISTICS</b>	
	Revised WRITE CYCLE 1,2 in TIMING WAVEFORMS	



# AS7C34098A-8TIN

### **FEATURES**

■ Fast access time: 8ns

■ Low power consumption:

Operating current: 50mA(TYP.) Standby current: 2mA(TYP.)

■ Single 3.3V power supply

■ All inputs and outputs TTL compatible

■ Fully static operation

■ Industrial temperature -40°~85°C

■ Tri-state output

■ Data byte control : LB# (DQ0 ~ DQ7)

UB# (DQ8 ~ DQ15)

Data retention voltage : 1.5V (MIN.)
Greenpackage/ROHS compliant (N)
Package : 44-pin 400 mil TSOP-II

### **GENERAL DESCRIPTION**

The AS7C34098A is a 4,194,304-bit high speed CMOS static random access memory organized as 262144 words by 16 bits. It is fabricated using very high performance, high reliability CMOS technology. Its standby current is stable within the range of operating temperature.

The AS7C34098A operates from a single power supply of 3.3V and all inputs and outputs are fully TTL compatible

### **PRODUCT FAMILY**

Product	Operating	Van Banga Spand		Vcc Range Speed Power Dissip	
Family	Temperature VCC Ra	Vcc Range	Speed	Standby(ISB1,TYP.)	Operating(Icc1,TYP.)
AS7C34098A(I)	-40°~85°C	3.0 ~ 3.6V	8ns	2mA	50mA

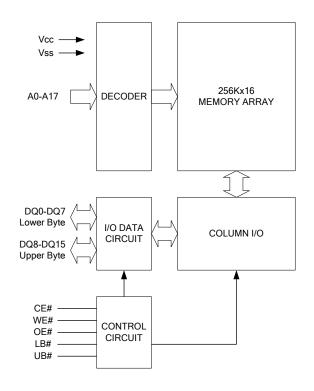
Tel: +1 650 610 6800 Fax: +1 650 620 9211

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# AS7C34098A-8TIN 256K X 16 BIT HIGH SPEED CMOS SRAM

## **FUNCTIONAL BLOCK DIAGRAM**



# **PIN DESCRIPTION**

SYMBOL	DESCRIPTION
A0 - A17	Address Inputs
DQ0 – D15	Data Inputs/Outputs
CE#	Chip Enable Inputs
WE#	Write Enable Input
OE#	Output Enable Input
LB#	Lower Byte Control
UB#	Upper Byte Control
Vcc	Power Supply
Vss	Ground
NC	No Connection

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# AS7C34098A-8TIN 256K X 16 BIT HIGH SPEED CMOS SRAM

## **PIN CONFIGURATION**

1				1
A0	1		44	A17
A1	2		43	A16
A2	3		42	A15
A3	4		41	OE#
A4	5		40	UB#
CE#	6		39	LB#
DQ0	7	_	38	DQ15
DQ1	8	Þ	37	DQ14
DQ2	9	S	36	DQ13
DQ3	10	888	35	DQ12
Vcc	11	\(\delta \) \(\delta \) \(\delta \)	34	Vss
Vss	12	34098, (XXX (XXX	33	Vcc
DQ4	13	$\mathcal{S} \mathcal{S} \mathcal{S}$	32	DQ11
DQ5	14	$\sim \sim \sim \sim \sim$	31	DQ10
DQ6	15	$\triangleright$	30	DQ9
DQ7	16		29	DQ8
WE#	17		28	NC
A5	18		27	A14
A6 <u></u>	19		26	A13
A7	20		25	A12
A8	21		24	A11
A9	22		23	A10
				J

TSOP II(Top View)



# AS7C34098A-8TIN 256K X 16 BIT HIGH SPEED CMOS SRAM

### **ABSOLUTE MAXIMUM RATINGS\***

PARAMETER	SYMBOL	RATING	UNIT
Voltage on Vcc relative to Vss	V <sub>T1</sub>	-0.5 to 4.6	V
Voltage on any other pin relative to Vss	VT2	-0.5 to Vcc+0.5	V
Operating Temperature	Та	-40 to 85(I grade)	$^{\circ}$
Storage Temperature	Тѕтс	-65 to 150	°C
Power Dissipation	PD	1	W
DC Output Current	Іоит	50	mA

<sup>\*</sup>Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to the absolute maximum rating conditions for extended period may affect device reliability.

### **TRUTH TABLE**

MODE	CE#	OE#	WE#	LB#	UB#	I/O OPERATION		SUPPLY CURRENT
IIIODE	02,,	02"	***		OD,	DQ0-DQ7	DQ8-DQ15	OOT I ET OOTKILLITT
Standby	Н	Х	Х	Х	Х	High – Z	High – Z	ISB,ISB1
Output Disable	L	Н	Н	Х	Х	High – Z	High – Z	lcc,lcc1
Output Disable	L	Х	Х	Н	Н	High – Z	High – Z	100,1001
	L	L	Н	L	Н	D <sub>OUT</sub>	High – Z	
Read	L	L	Н	Н	L	High – Z	$D_OUT$	lcc,lcc1
	L	L	Н	L	L	$D_OUT$	$D_OUT$	
	L	Х	L	L	Н	D <sub>IN</sub>	High – Z	
Write	L	Х	L	Н	L	High – Z	$D_IN$	lcc,lcc1
	L	Х	L	L	L	$D_IN$	$D_IN$	

Note: H = V<sub>IH</sub>, L = V<sub>IL</sub>, X = Don't care



# AS7C34098A-8TIN 256K X 16 BIT HIGH SPEED CMOS SRAM

### **DC ELECTRICAL CHARACTERISTICS**

PARAMETER	SYMBOL	TEST CONDITION		MIN.	TYP. *4	MAX.	UNIT
Supply Voltage	Vcc	-8	3	3.0	3.3	3.6	V
Input High Voltage	V <sub>IH</sub> <sup>*1</sup>			2.2	-	Vcc+0.3	V
Input Low Voltage	V <sub>IL</sub> <sup>2</sup>			- 0.3	-	8.0	V
Input Leakage Current	ILI	$V_{CC} \ge V_{IN} \ge V_{SS}$		- 1	-	1	μA
Output Leakage Current	ILO	V <sub>CC</sub> ≧ V <sub>OUT</sub> ≧ V <sub>SS</sub> , Output Disabled		- 1	-	1	μΑ
Output High Voltage	Vон	I <sub>OH</sub> = -4mA		2.4	-	-	V
Output Low Voltage	Vol	I <sub>OL</sub> = 8mA		-	-	0.4	V
Average Operating	Icc	Cycle time = Min. CE# = V <sub>IL</sub> , I <sub>I/O</sub> = 0mA, Others at V <sub>IL</sub> or V <sub>IH</sub>	-8	-	65	80	mA
Power supply Current	Icc1	CE# $\leq$ 0.2, Others at 0.2V or Vcc-0.2V I <sub>I/O</sub> = 0mA;f=max	-8	-	50	60	mA
Standby Power	IsB	CE# =V <sub>IH</sub> , Others at V <sub>IL</sub> or V	IH	-	-	30	mΑ
Supply Current	I <sub>SB1</sub>	CE# $\geq$ V <sub>CC</sub> - 0.2V, Others at 0.2V or V <sub>CC</sub> - 0.2V		-	2	10	mA

#### Notes:

- 1.  $V_{IH}(max) = V_{CC} + 2.0V$  for pulse width less than 6ns.
- 2. VIL(min) = Vss 2.0V for pulse width less than 6ns.
- 3. Over/Undershoot specifications are characterized on engineering evaluation stage, not for mass production test.
- 4. Typical values are included for reference only and are not guaranteed or tested. Typical valued are measured at  $V_{CC}$  =  $V_{CC}$ (TYP.) and  $T_A$  = 25°C

### CAPACITANCE (TA = 25%, f = 1.0MHz)

PARAMETER	SYMBOL	MIN.	MAX	UNIT
Input Capacitance	Cin	-	8	pF
Input/Output Capacitance	C <sub>I/O</sub>	-	10	pF

Note: These parameters are guaranteed by device characterization, but not production tested.

### **AC TEST CONDITIONS**

Speed	8ns
Input Pulse Levels	0.2V to V <sub>CC</sub> - 0.2V
Input Rise and Fall Times	3ns
Input and Output Timing Reference Levels	1.5V
Output Load	$C_L = 30pF + 1TTL$ , $I_{OH}/I_{OL} = -4mA/8mA$



# AS7C34098A-8TIN 256K X 16 BIT HIGH SPEED CMOS SRAM

### **AC ELECTRICAL CHARACTERISTICS**

### (1) READ CYCLE

PARAMETER	SYM.	AS7C34	AS7C34098A-8		
FARAWLILK	STIVI.	MIN.	MAX.	UNIT	
Read Cycle Time	trc	8	-	ns	
Address Access Time	taa	-	8	ns	
	<b>t</b> ace	-	8	ns	
	toe	-	4.5	ns	
	tclz*	2	-	ns	
· ·	tolz*	0	-	ns	
, ,	tcнz*	-	3	ns	
Output Disable to Output in High-Z	toнz*	-	3	ns	
Output Hold from Address Change	tон	2	-	ns	
LB#, UB# Access Time	tва	-	4.5	ns	
LB#, UB# to High-Z Output	t <sub>BHZ</sub> *	-	3	ns	
LB#, UB# to Low-Z Output	t <sub>BLZ</sub> *	0	-	ns	

#### (2) WRITE CYCLE

PARAMETER	SYM.	AS7C34	UNIT	
PARAWETER	STIVI.	MIN.	MAX.	UNIT
Write Cycle Time	twc	8	-	ns
Address Valid to End of Write	taw	6.5	-	ns
Chip Enable to End of Write	tcw	6.5	-	ns
Address Set-up Time	<b>t</b> as	0	-	ns
Write Pulse Width	twp	6.5	-	ns
Write Recovery Time	twr	0	-	ns
Data to Write Time Overlap	tow	5	-	ns
Data Hold from End of Write Time	tон	0	-	ns
Output Active from End of Write	tow*	2	-	ns
Write to Output in High-Z	twnz*	-	3	ns
LB#, UB# Valid to End of Write	t <sub>BW</sub>	6.5	ı	ns

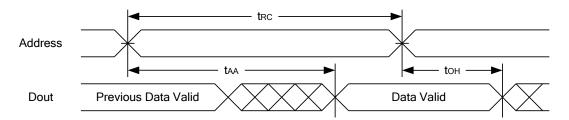
<sup>\*</sup>These parameters are guaranteed by device characterization, but not production tested.



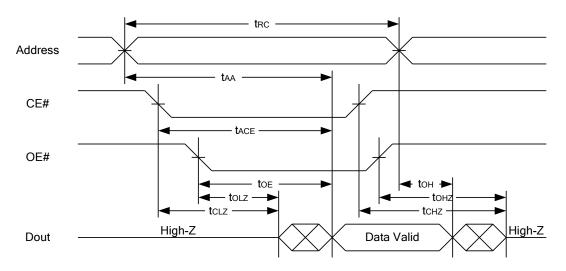
# AS7C34098A-8TIN 256K X 16 BIT HIGH SPEED CMOS SRAM

### **TIMING WAVEFORMS**

#### READ CYCLE 1 (Address Controlled) (1,2)



## READ CYCLE 2 (CE# and OE# Controlled) (1,3,4,5)



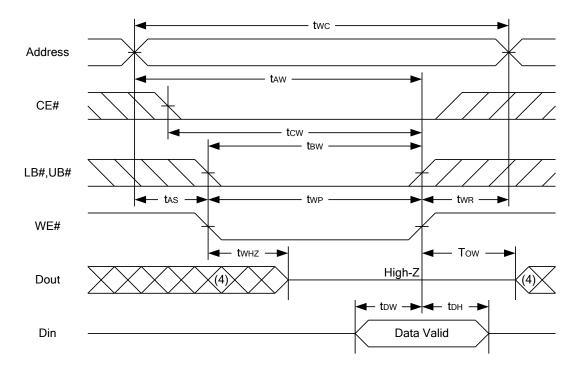
#### Notes:

- 1.WE# is high for read cycle.
- 2.Device is continuously selected OE# = low, CE# = low.
- 3.Address must be valid prior to or coincident with CE# = low,; otherwise tAA is the limiting parameter.
- 4.tclz, tolz, tchz and tohz are specified with CL = 5pF. Transition is measured ±500mV from steady state.
- 5.At any given temperature and voltage condition, tcHz is less than tcLz, toHz is less than toLz.

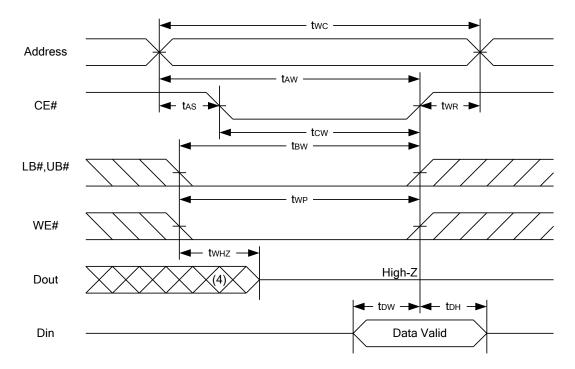


# AS7C34098A-8TIN 256K X 16 BIT HIGH SPEED CMOS SRAM

#### WRITE CYCLE 1 (WE# Controlled) (1,2,3,5,6)



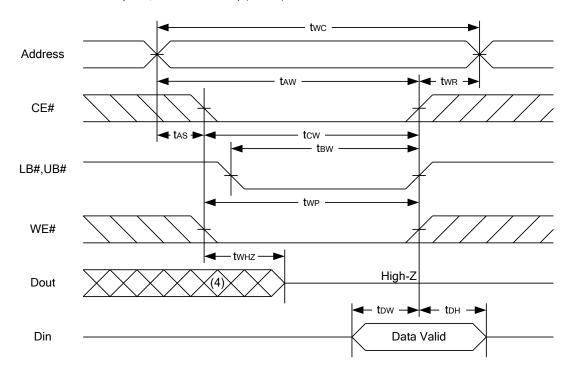
### WRITE CYCLE 2 (CE# Controlled) (1,2,5,6)





# AS7C34098A-8TIN 256K X 16 BIT HIGH SPEED CMOS SRAM

#### WRITE CYCLE 3 (LB#,UB# Controlled) (1,2,5,6)



#### Notes:

- 1.WE#,CE#, LB#, UB# must be high during all address transitions.
- 2.A write occurs during the overlap of a low CE#, low WE#, LB# or UB# = low.
- 3.During a WE# controlled write cycle with OE# low, twp must be greater than twnz + tow to allow the drivers to turn off and data to be placed on the bus.
- 4. During this period, I/O pins are in the output state, and input signals must not be applied.
- 5.If the CE#, LB#, UB# low transition occurs simultaneously with or after WE# low transition, the outputs remain in a high impedance
- 6.tow and twHz are specified with CL = 5pF. Transition is measured ±500mV from steady state.



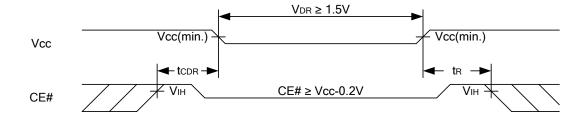
# AS7C34098A-8TIN 256K X 16 BIT HIGH SPEED CMOS SRAM

## **DATA RETENTION CHARACTERISTICS**

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Vcc for Data Retention	V <sub>DR</sub>	CE# ≧ Vcc - 0.2V	1.5	-	3.6	V
Data Retention Current	I <sub>DR</sub>	V <sub>CC</sub> = 1.5V CE# ≧ V <sub>CC</sub> - 0.2V Others at 0.2V or V <sub>CC</sub> - 0.2V	-	2	10	mA
Chip Disable to Data Retention Time	tcdr	See Data Retention Waveforms (below)	0	-	-	ns
Recovery Time	tR		t <sub>RC*</sub>	-	-	ns

tRC∗ = Read Cycle Time

### **DATA RETENTION WAVEFORM**

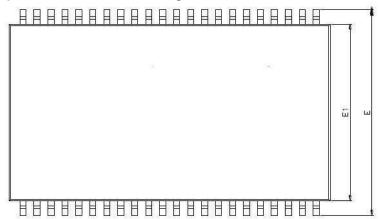


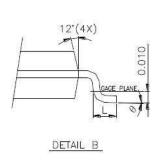


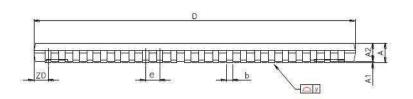
# AS7C34098A-8TIN 256K X 16 BIT HIGH SPEED CMOS SRAM

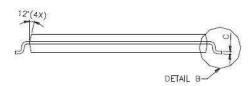
## **PACKAGE OUTLINE DIMENSION**

## 44-pin 400mil TSOP-II Package Outline Dimension









SYMBOLS	DIMENSIONS IN MILLMETERS			DIMENSIONS IN MILS		
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.
Α	-	-	1.20	-	-	47.2
A1	0.05	0.10	0.15	2.0	3.9	5.9
A2	0.95	1.00	1.05	37.4	39.4	41.3
b	0.30	-	0.45	11.8	-	17.7
С	0.12	-	0.21	4.7	-	8.3
D	18.212	18.415	18.618	717	725	733
E	11.506	11.760	12.014	453	463	473
E1	9.957	10.160	10.363	392	400	408
е	-	0.800	-	-	31.5	-
L	0.40	0.50	0.60	15.7	19.7	23.6
ZD	-	0.805	-	- 1	31.7	- 1
У	-	i	0.076	-	-	3
θ	0°	3°	6°	0°	3°	6°



# AS7C34098A-8TIN

#### ORDERING INFORMATION

Package Type	Access Time (Speed/ns)	Temperature Range(℃)	Packing Type	Alliance Memory Part No.
44Pin(400mil)	8	-40℃~85℃		AS7C34098A-8TIN
TSOP-II			Tape Reel	AS7C34098A-8TINTR



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# AS7C34098A-8TIN 256K X 16 BIT HIGH SPEED CMOS SRAM

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